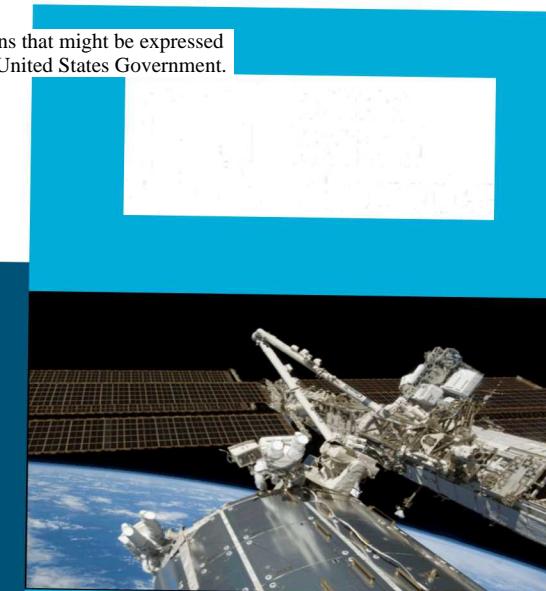


# Introduction to the Space Radiation Environment



*PRESENTED BY*

Paul Thelen



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# Introduction

The space environment contains various sources of radiation

Radiation interacts in unique ways with matter

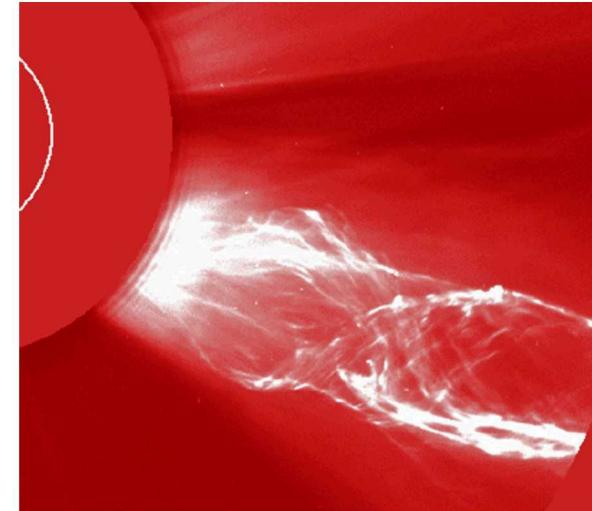
Radiation effects can have detrimental results on electronics  
if not properly mitigated

Need to understand ...

- The space radiation environment
- Radiation effects on matter
- How to mitigate radiation effects

... In order to:

- Design radiation tolerant electronic components and integrated circuits
- Design a robust spacecraft
- Predict performance degradation and/or potential failure of systems in space



From SOHO -- Solar and Heliospheric Observatory

# Agenda

## Environment

- Galactic Cosmic Rays
- Solar Particle Events
- Van Allen Belts

## Effects

- Total Ionizing Dose
- Single Event Effects
- Displacement Damage
- Spacecraft Charging

# Environment Intro – The Sun

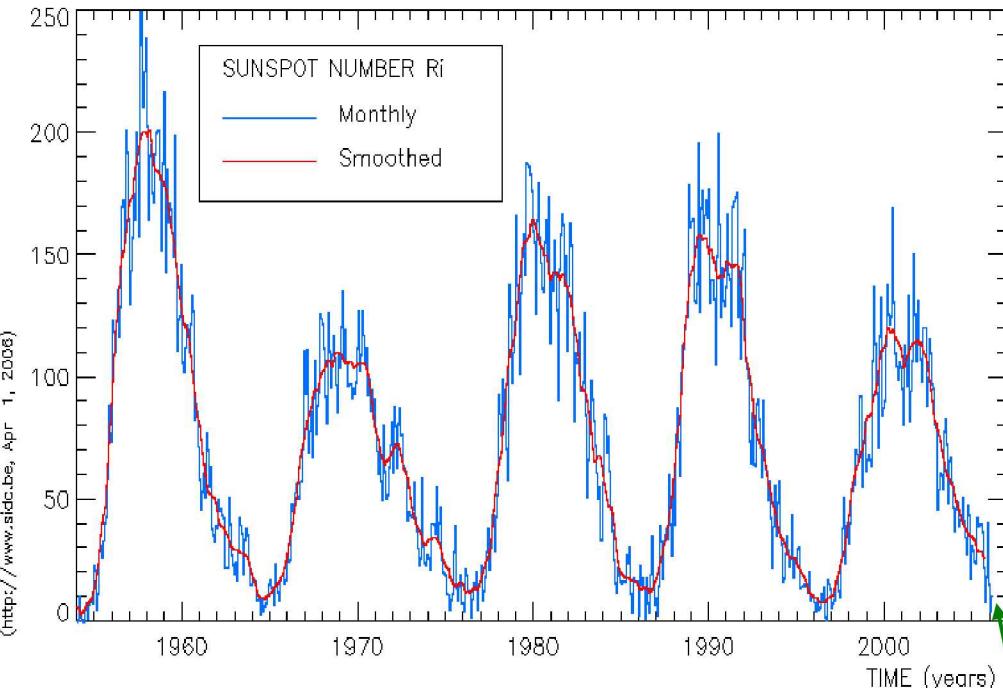
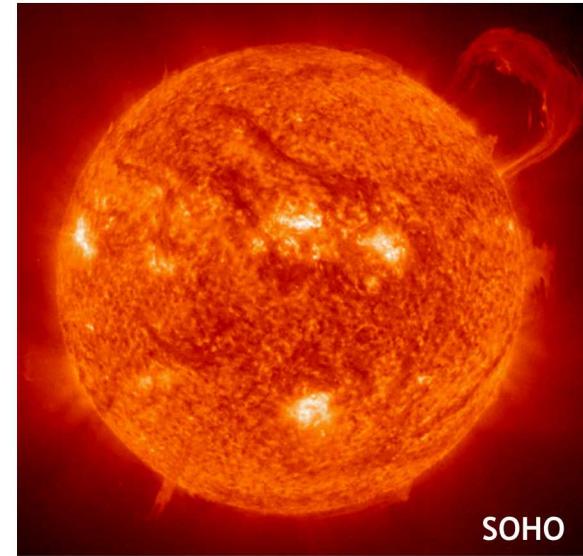
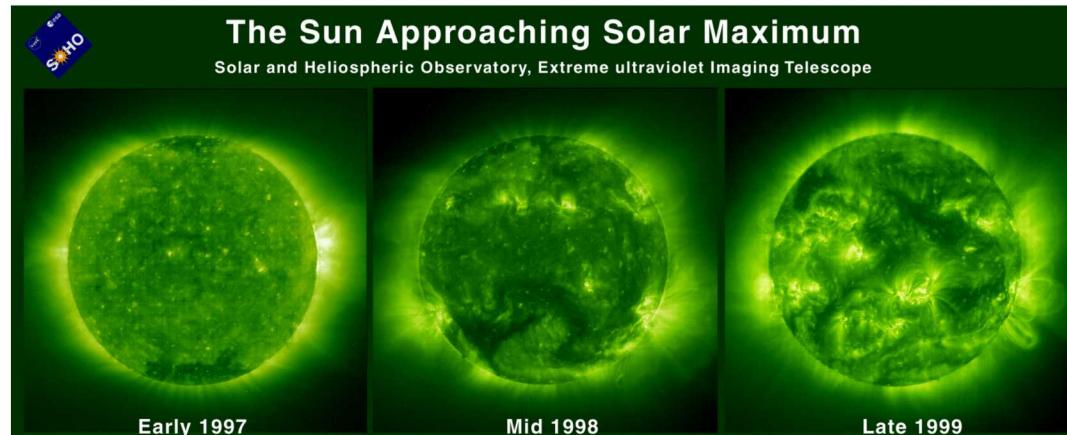


The sun is the main source of radiation in our solar system

Follows an 11 year cycle of low to high activity (based on changes in magnetic field)

How do we know about the cycle?

- Increased magnetic activity leads to increase sunspot number and increased solar particle events (SPE)
- Increased SPE deflect cosmic rays which decreases Carbon-14 production in Earth's atmosphere
- Decrease carbon-14 shows up in tree rings



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# Galactic Cosmic Rays

Galactic Cosmic Rays (GCR) are

- Low flux – low rate of interaction with a device
- Extremely high energy (GeV and higher), thus potentially can deposit a lot of energy into a device
- Mostly hydrogen and helium, although can be comprised of any element
- Probably originated from supernovas
- Deflected by solar activity

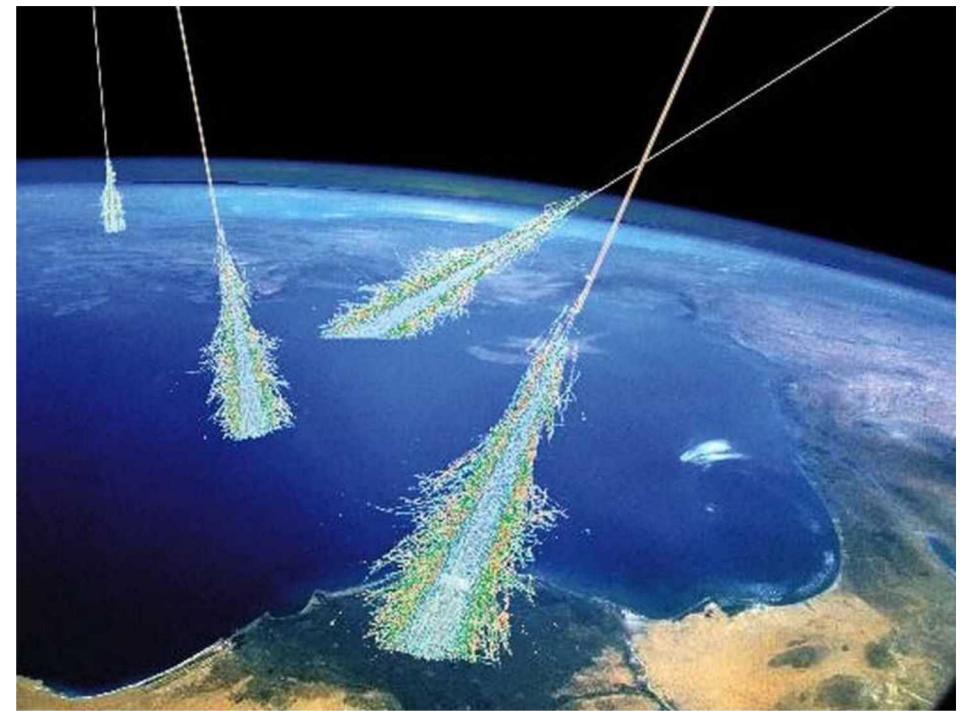
Supernova Remnants



Cygnus Loop



N 63A

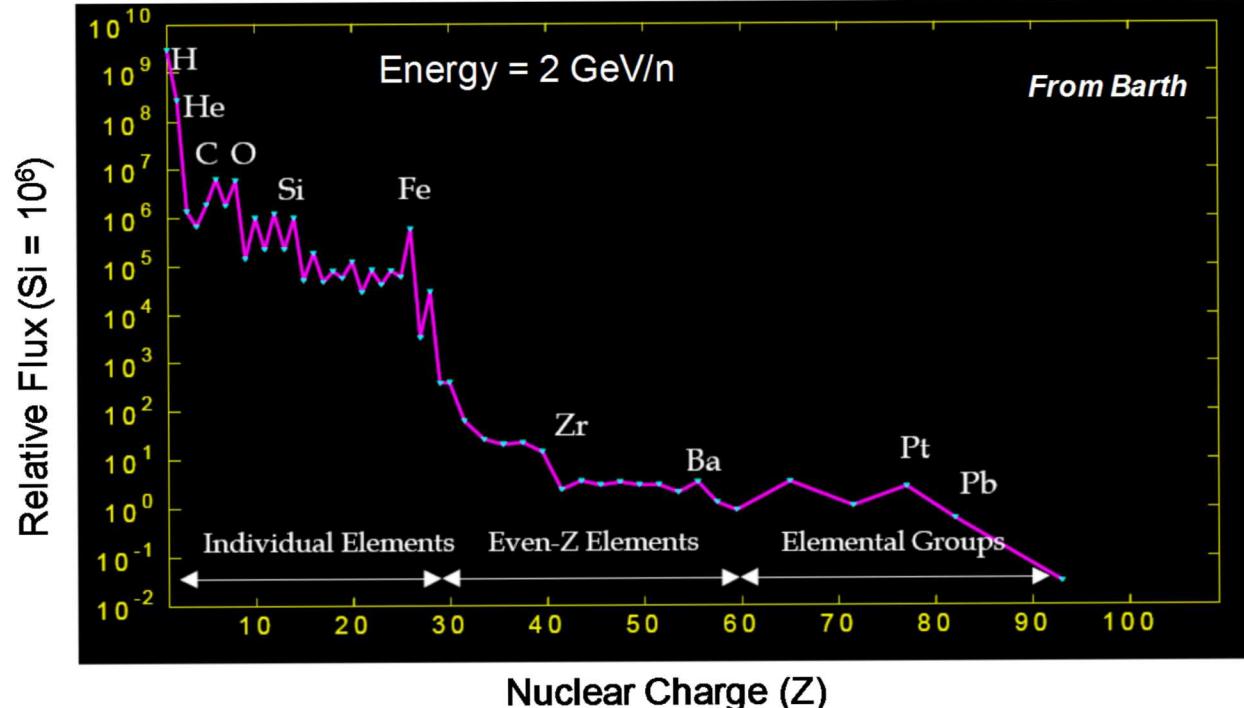
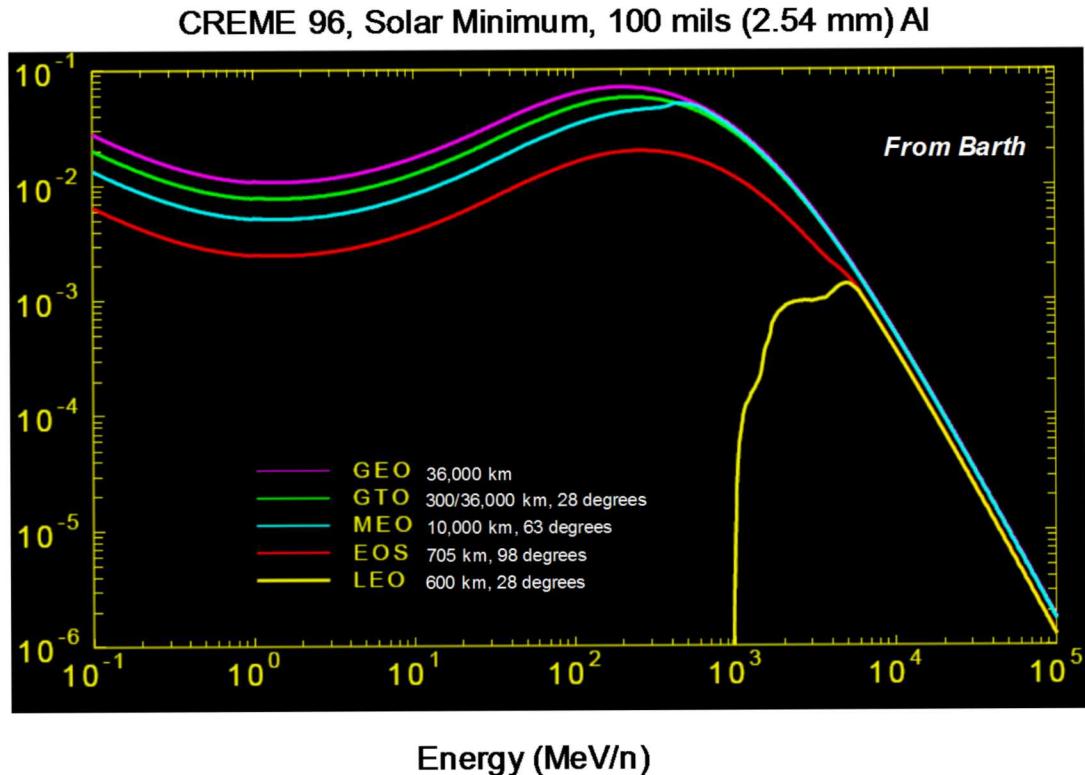


Credit: Simon Swordy (U. Chicago), NASA

Steady, low-flux, very high energy

# Galactic Cosmic Rays

Particles (#/cm<sup>2</sup>/day/MeV/nuc)



## Solar Particle Event

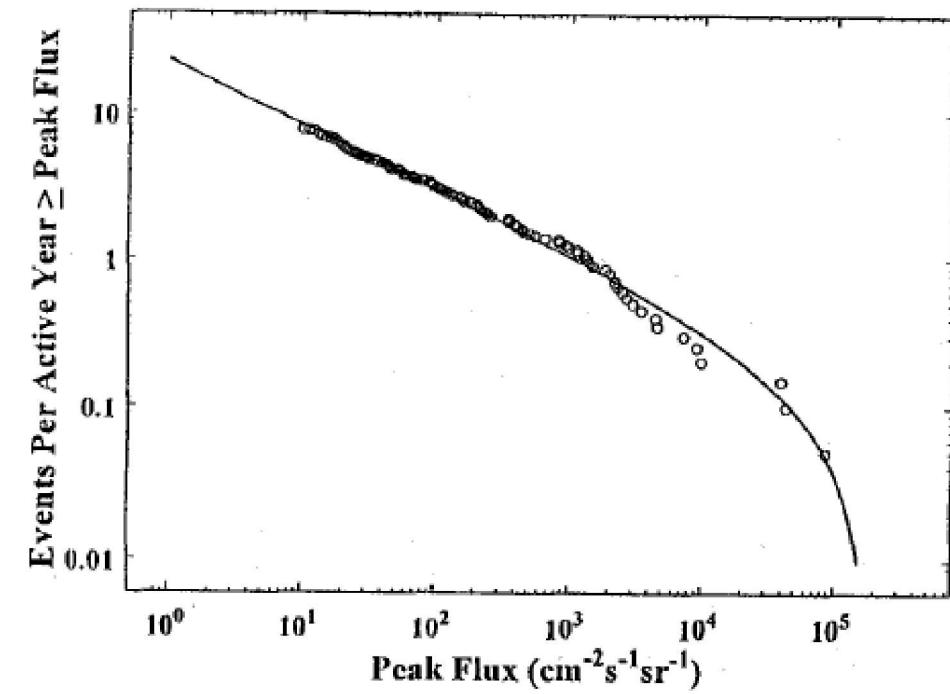
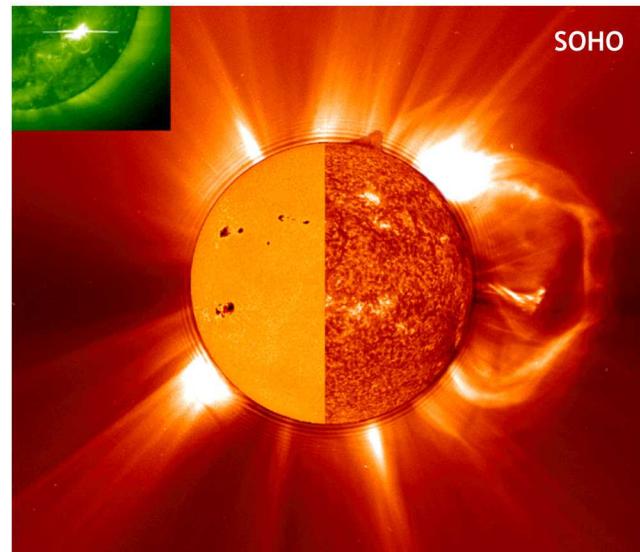
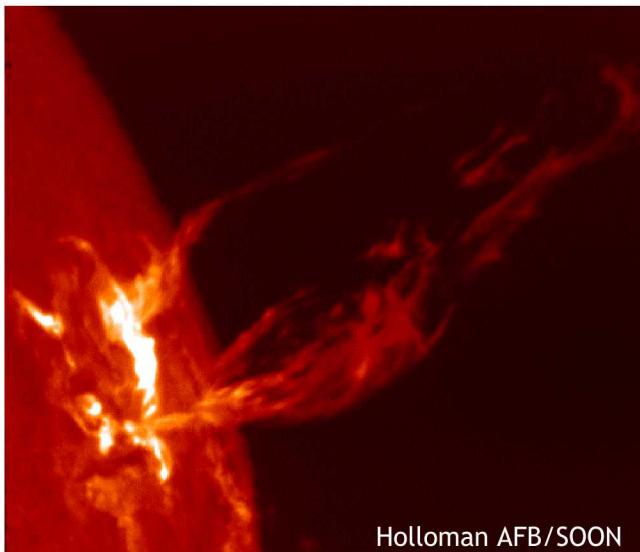
Solar Particle Events (SPE) are material ejected from the sun due to its magnetic field

More SPEs during solar maximum in 11 year cycle

SPEs last hours to days

SPEs are coronal mass ejections and solar flares

Large events are less frequent (right)



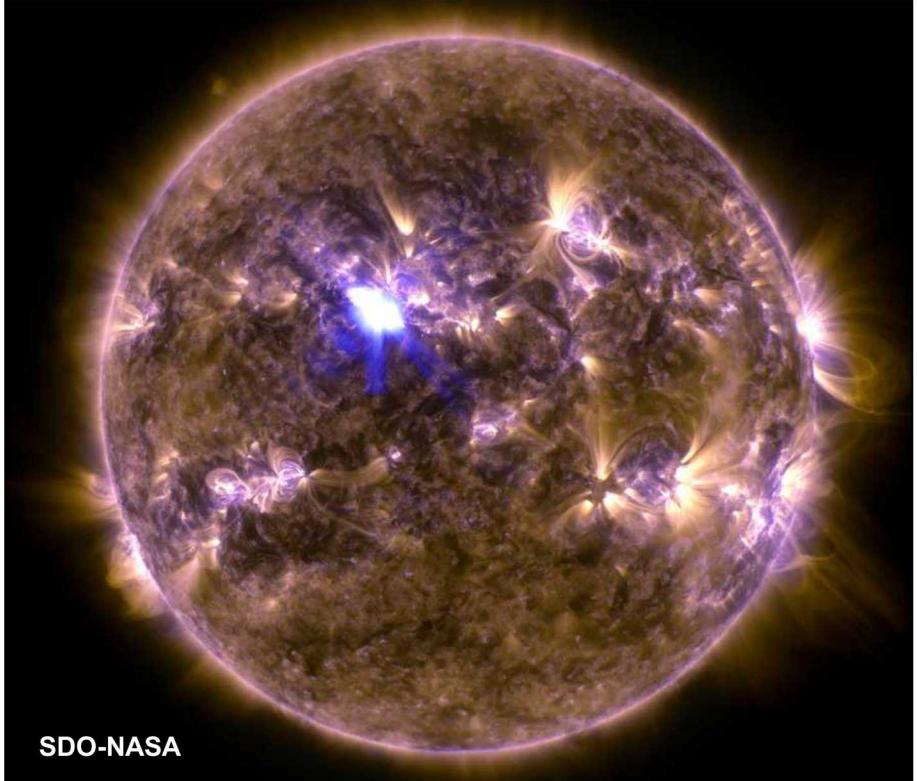
M.A. Xapsos, "Probability Model for Peak Fluxes of Solar Proton Events, IEEE TNS Vol.45, p. 2948, 1998

Cyclic, with random/violent events, high flux, high energy

# 9 Solar Particle Event



Composite false-color  
Extreme-UV image of the Sun



Proton flux data taken by the GOES 13 satellite –  
data at Space Weather Prediction Center website

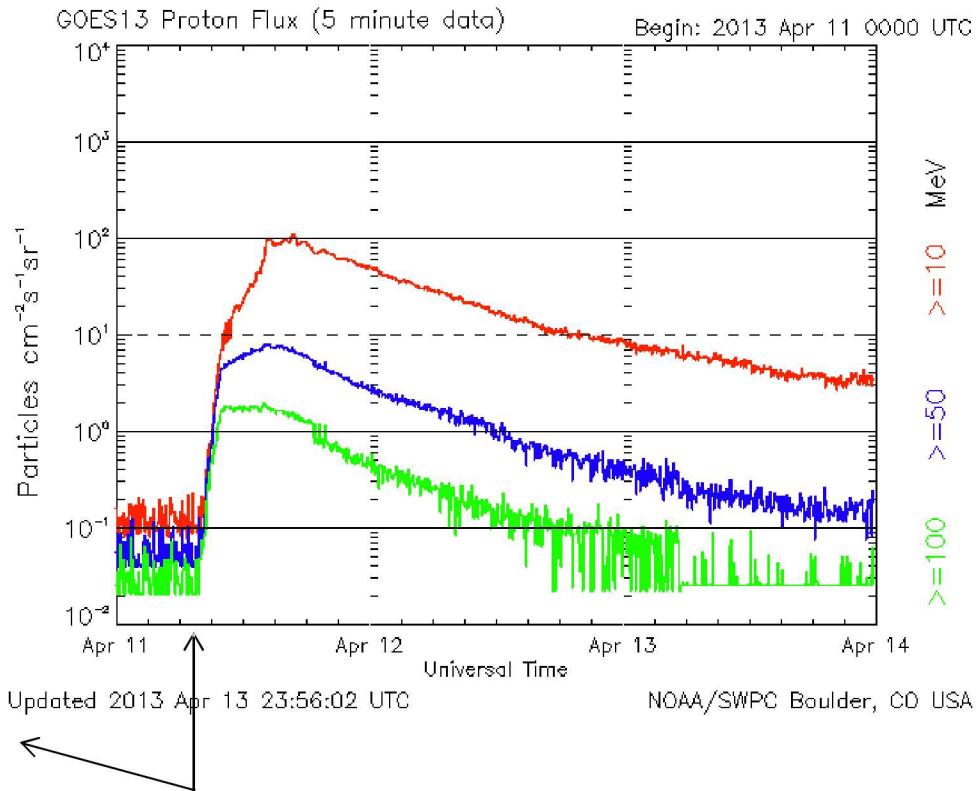


Image of solar flare  
taken at 0711 UTC 4/11

# Van Allen Belts

Earth's magnetic field traps electrons and protons

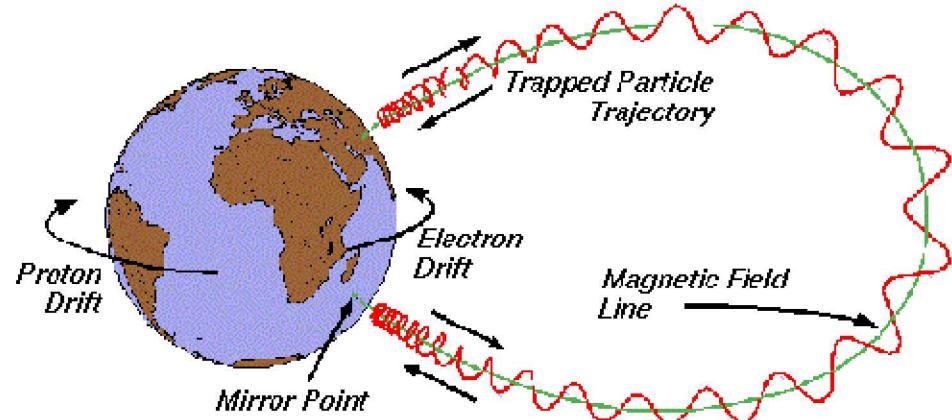
Captures particles from solar wind/solar events and GCR interactions in atmosphere

Particles travel back and forth, trapped for years

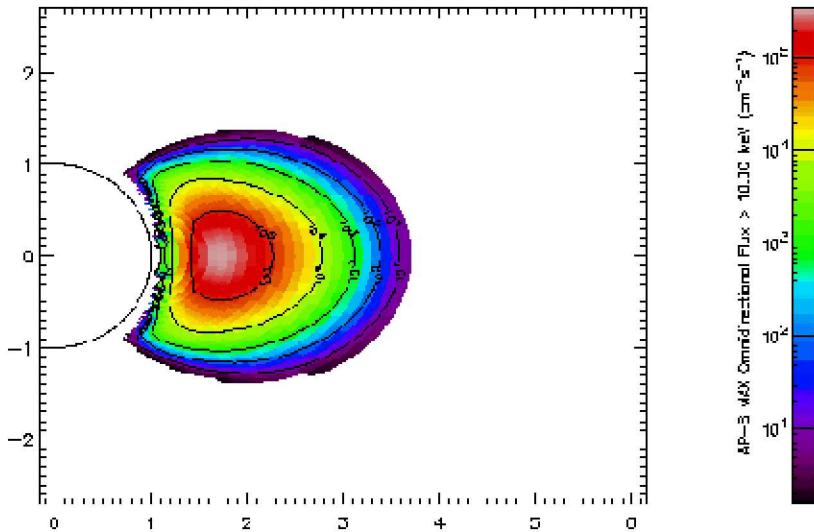
Belts dip very close in south Atlantic

Proton energy: 100 keV to 100 MeV+

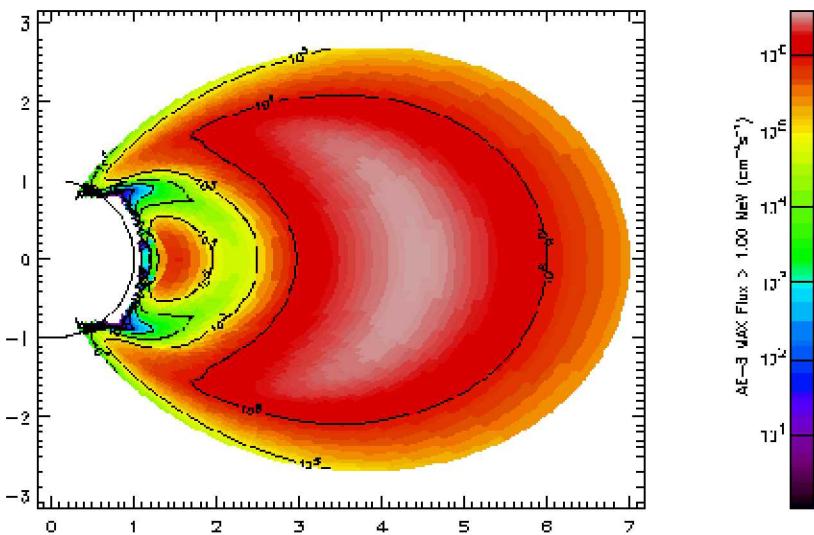
Electron energy: 10 keV to 10 MeV+



SPENVIS website



Trapped Proton Belt AP-8 MAX integral proton flux  $> 10$  MeV

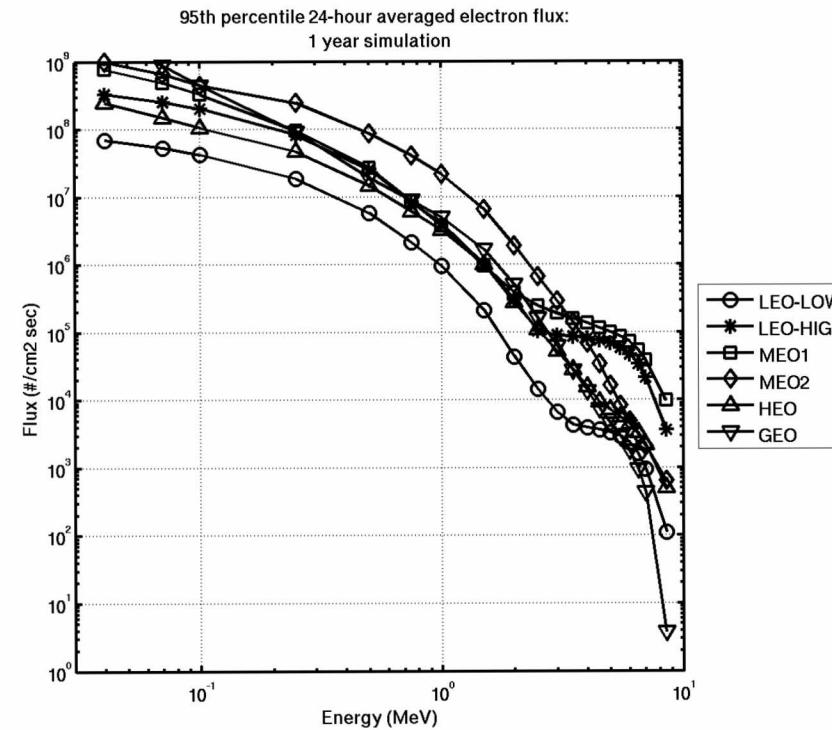
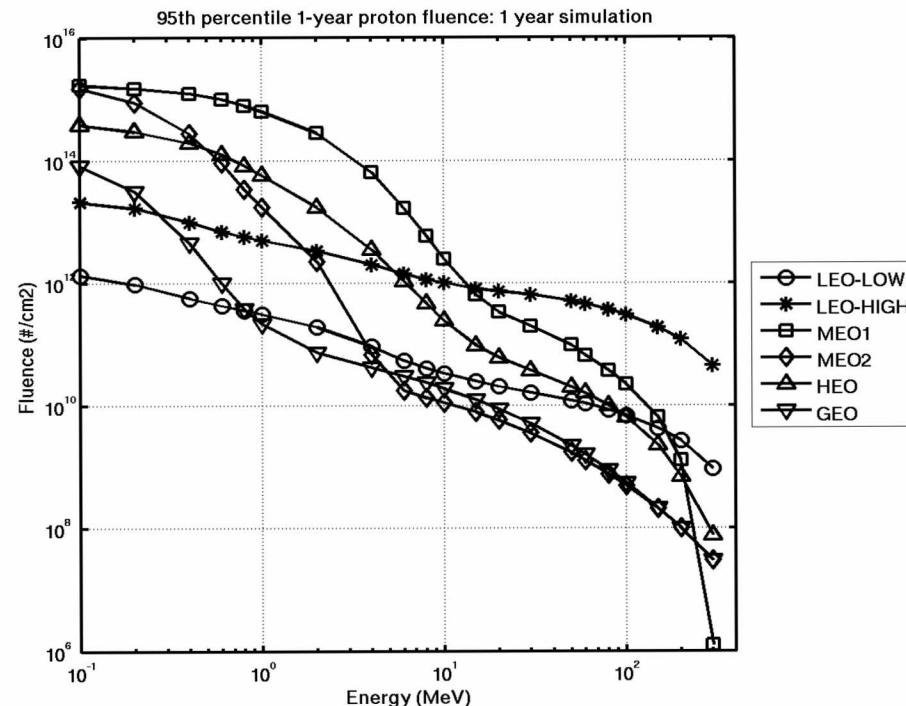


Trapped Electron Belt AE-8 MAX integral electron flux  $> 1$  MeV

Steady, low energy, very high flux

# Van Allen Belts

From Mark Johnson, Aerospace Corp



Orbit	Altitude	Inclination
	km	degrees
LEO-LOW	$\leq 800$	All
LEO-HIGH	$\leq 2000$	All
MEO1	8062	0
MEO2	20200	55
HEO	1000 to 39478	63.4
GEO	35870	0

Complex. Need model for high fidelity of specific orbit

# Agenda

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## Effects

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- Single Event Effects
- Displacement Damage
- Spacecraft Charging

Mechanism, Effect, Mitigation

# Total Ionizing Dose (TID)

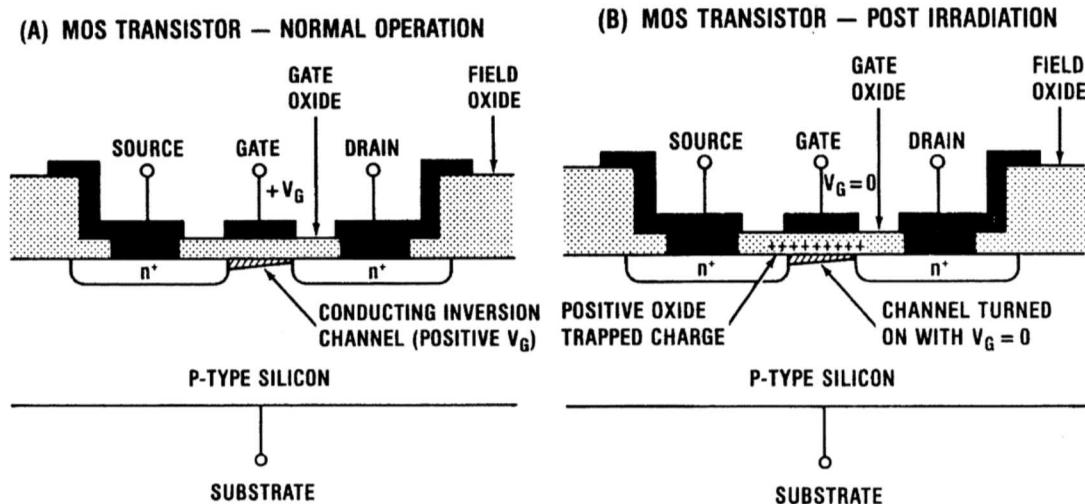
Protons and electrons will ionize electronics  
(the effect is most prevalent in MEO)

Constantly accumulated slowly over time

Some charge will be trapped

Leads to various effects

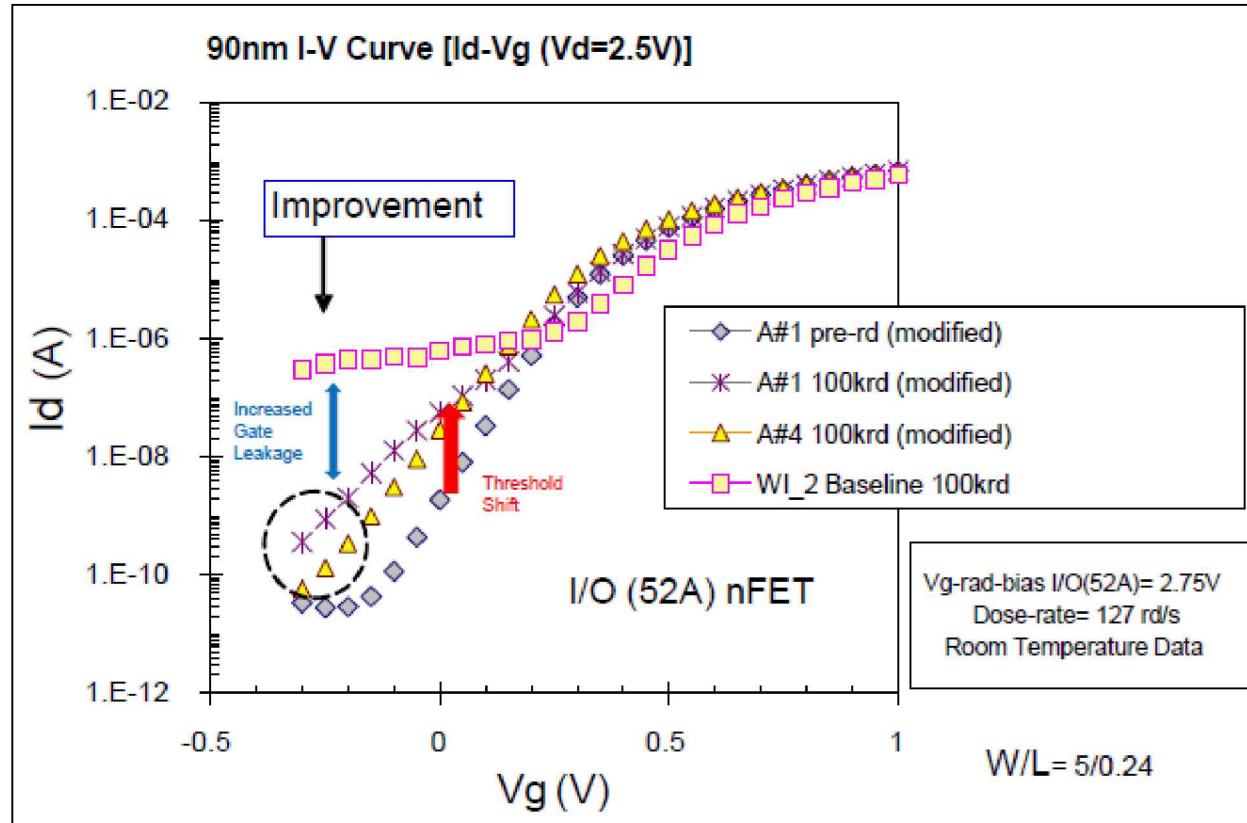
- Threshold shifts
- Leakage currents
- Timing changes
- Functional failures



Trapped Charge in a MOS transistor  
T.R. Oldham, and F.B. McLean, "Total Ionizing Dose  
Effects in MOS Oxides and Devices," *IEEE Trans. Nucl. Sci.*,  
vol. 50, no. 3,  
p. 483, June 2003.

COTS may fail 5-20 krad  
Rad hard parts can survive much higher doses  
(100 krad, 300 krad, etc.)

## TID Example



nFET TID Damage  
From Bruce Wilson, DTRA

# TID Mitigation

## Shielding

- Shielding can reduce TID of a given part
- If a part cannot meet TID requirements for a given orbit/depth combination, shielding can supplement
- High-Z material has a better aluminum equivalence, and makes for a better shield to weight ratio in general

## Part Selection

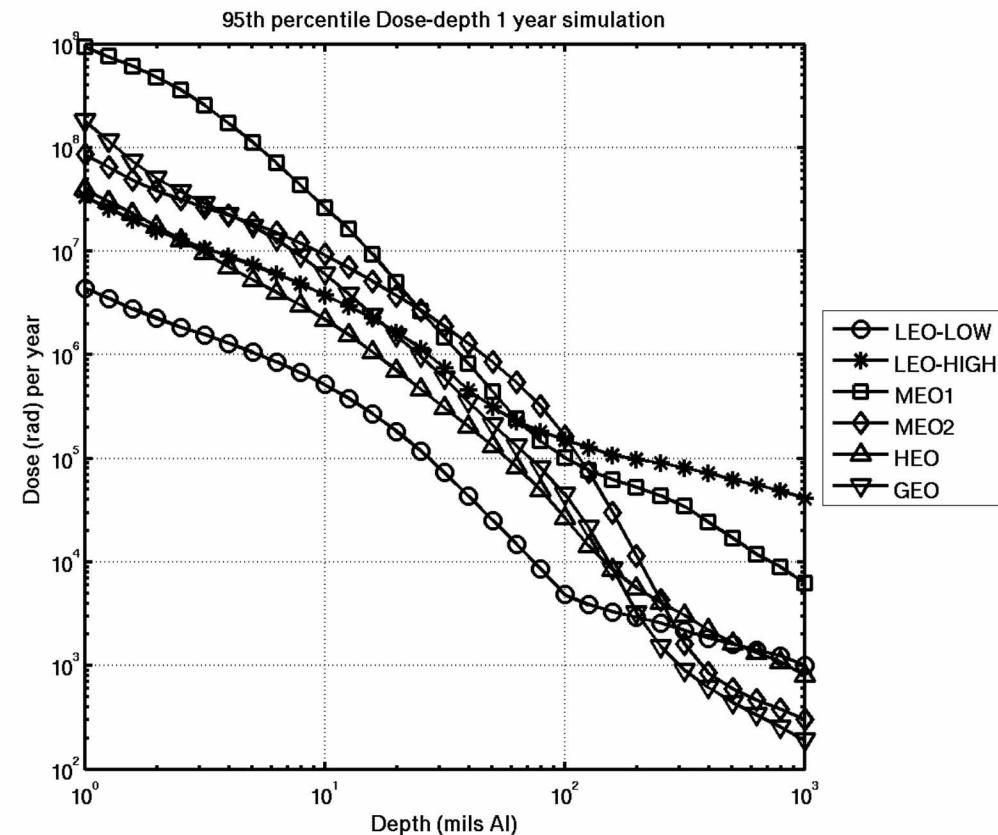
- Rad hardened/Rad tolerant parts are almost always referring to TID hardened
- Select parts that are radiation tolerant/hardened against space radiation

## Design

- Parts deeper in the space vehicle receive lower TID due to shielding from other components

## Orbit Selection

- TID varies with orbit (right)



From Mark Johnson, Aerospace Corp

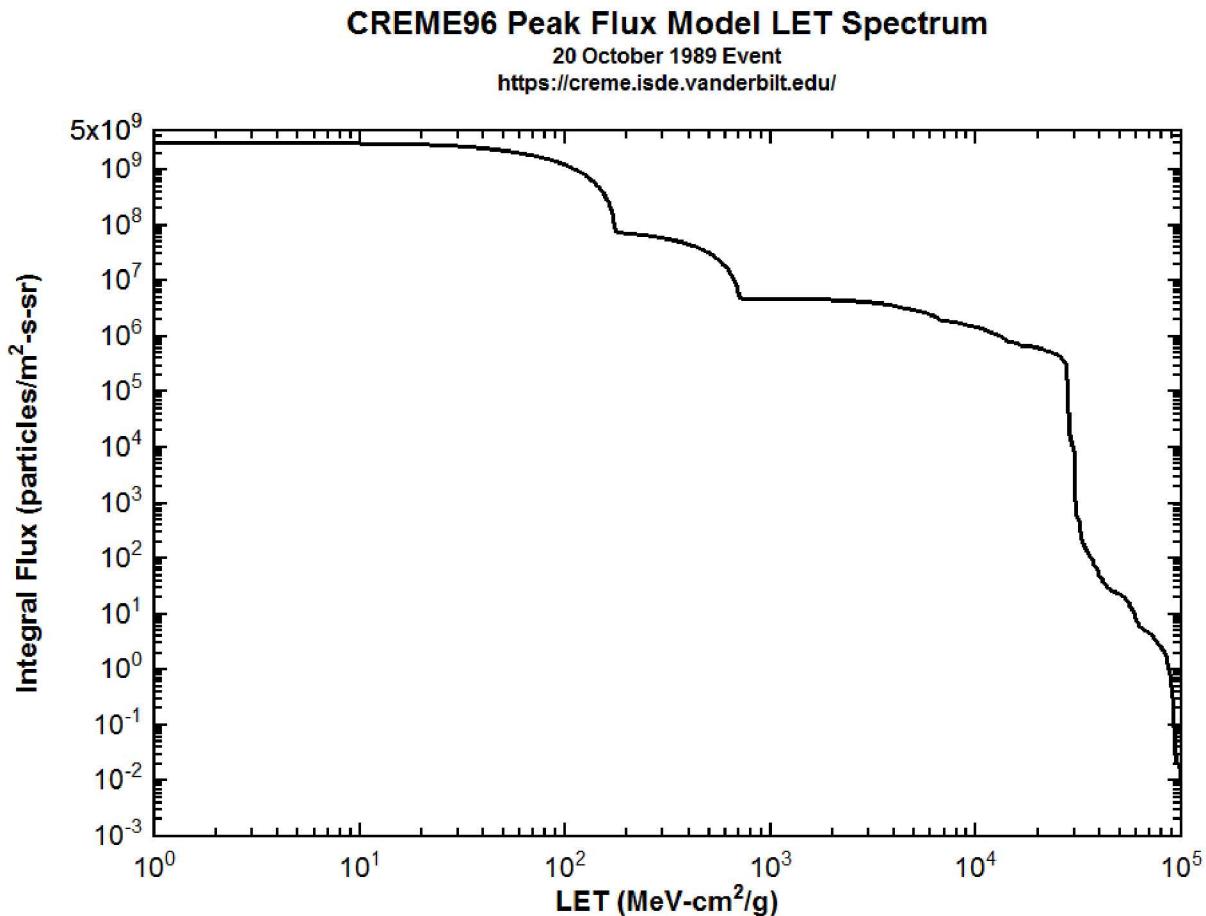
# Single Event Effects

Protons, heavy ions and electrons deposit energy in semiconductor material

Neutrons may induce reactions that indirectly deposit charge

Depending on linear energy transfer (LET) of particle, various effects are possible

- Soft errors: Single Event Upset (SEU), Single Event Transient (SET)
- Hard errors: Single Event Latchup (SEL), Single Event Burnout (SEB), Single Event Gate Rupture (SEGR)



From Mark Johnson, Aerospace Corp

## Soft Errors

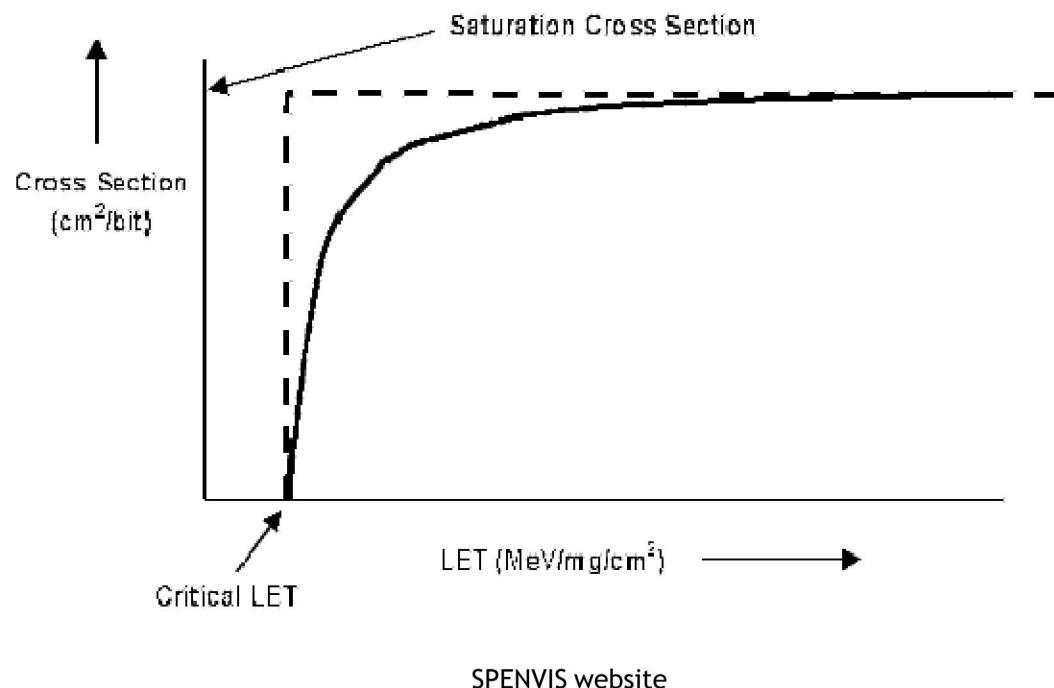
SEU is a state change in logic element (memory bit) induced from deposited charge

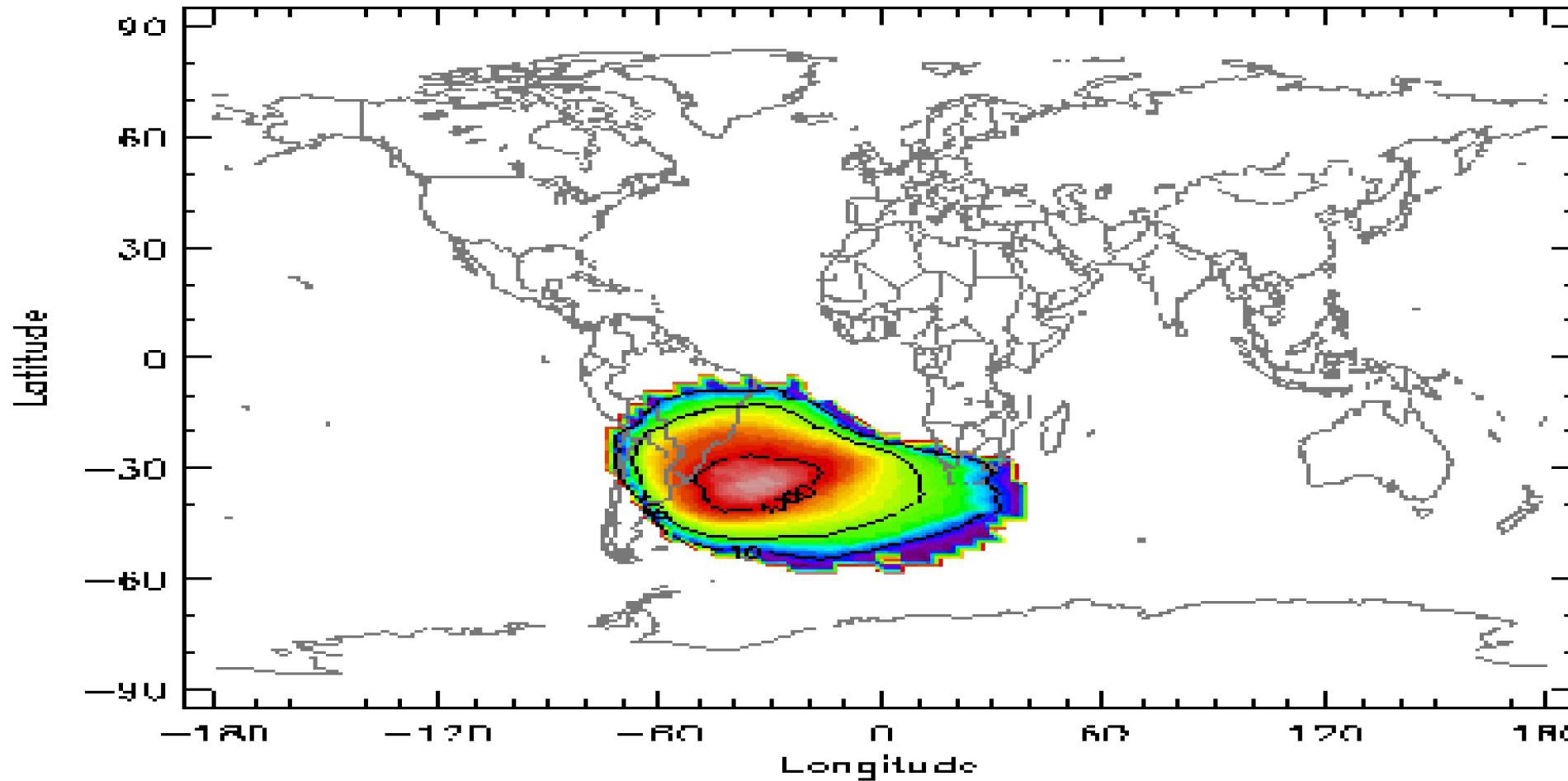
Requires some minimum, critical amount of charge

Thus, requires some minimum LET (usually a low value)

Mitigation:

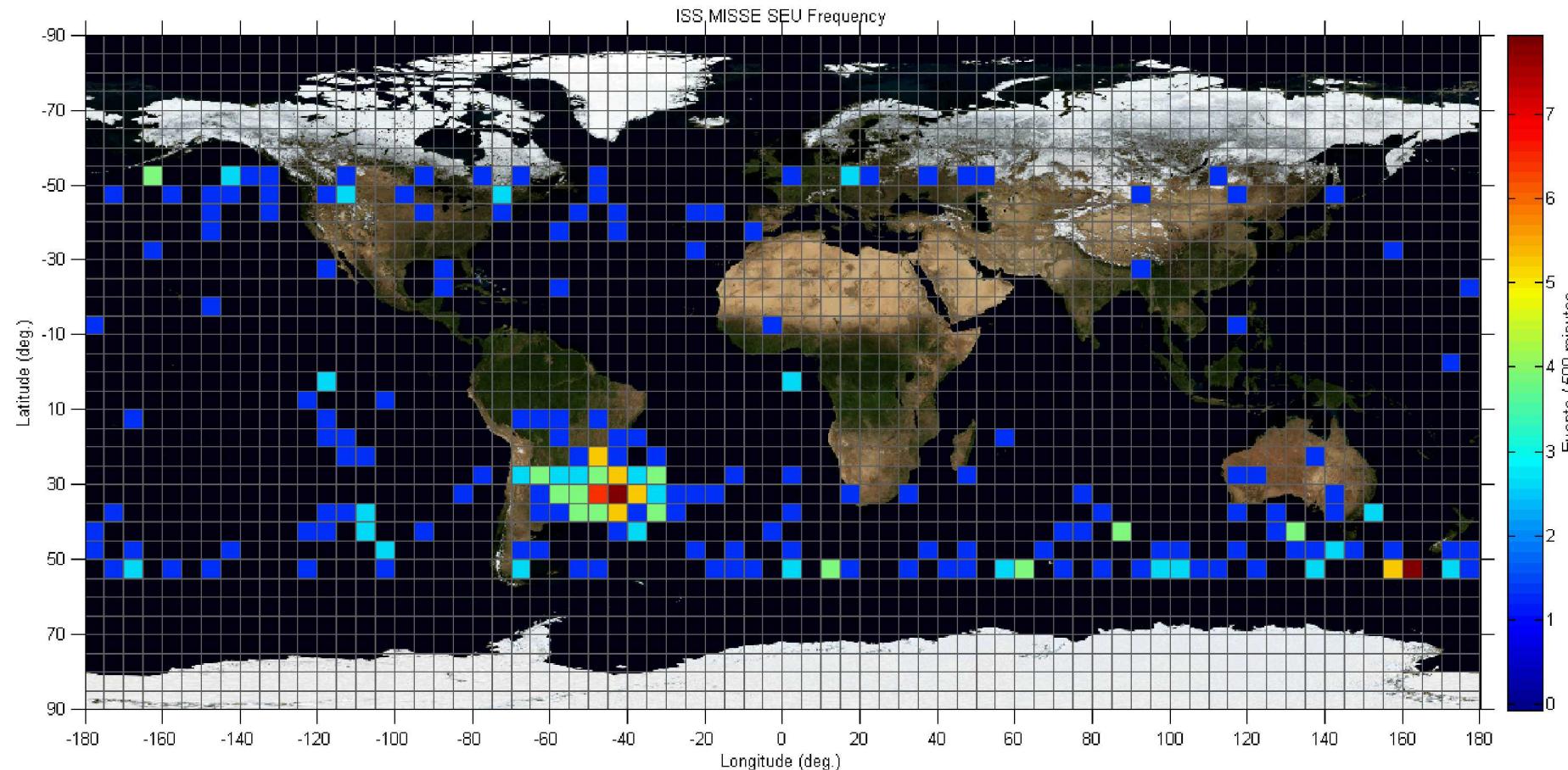
- Error detection and correction (EDAC) through redundancy or other strategies. Higher rates make EDAC difficult (multiple bit upset - simultaneous)
- Part selection (requires higher LET for upset, lower upset cross-section/rate)
- Test – proton or ion source
- Orbit Selection (next slide)



Soft Errors - AE-8 Trapped Proton  $E > 10$  MeV at 500 km



### *SEU Upset Rates in Xilinx Virtex FPGAs on SEUXSE/MISSE7A on the ISS*



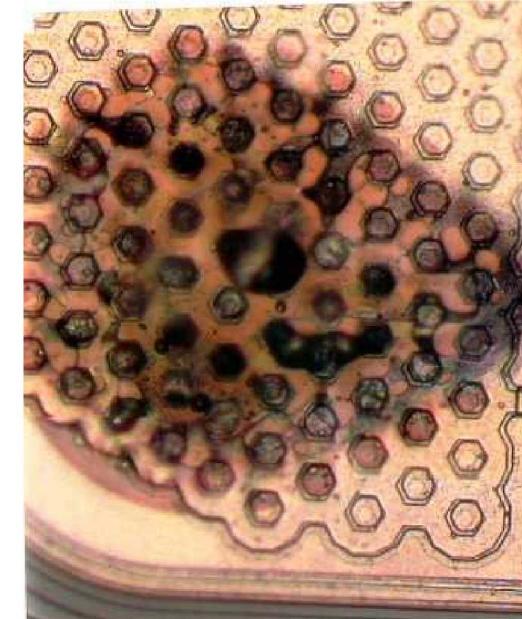
## Hard Errors

Higher critical charge, but usually larger consequence

Often leads to high current modes that ultimately cause part failure

Mitigation:

- Part selection – (requires higher LET for event, lower event cross-section/rate)
- Test – ion source (to get higher LET)
- Detection of high current, circumvent and recover



*From "Programmable Logic in the Space Radiation Environment",  
Kenneth A. LaBel, NASA Goddard Space Flight Center*

## Displacement Damage

Protons, electrons and neutrons will push lattice of electronics (especially prevalent in low-MEO/high-LEO)

Proton dominate

Constantly accumulated over time, leads to lattice vacancies and interstitials

Defects can become trapping/recombination sites

Leads to various effects

- Lower minority carrier lifetime
- Lower transistor gain
- Optical degradation

Mostly mitigated through part selection, if orbit is an issue

# Spacecraft Charging

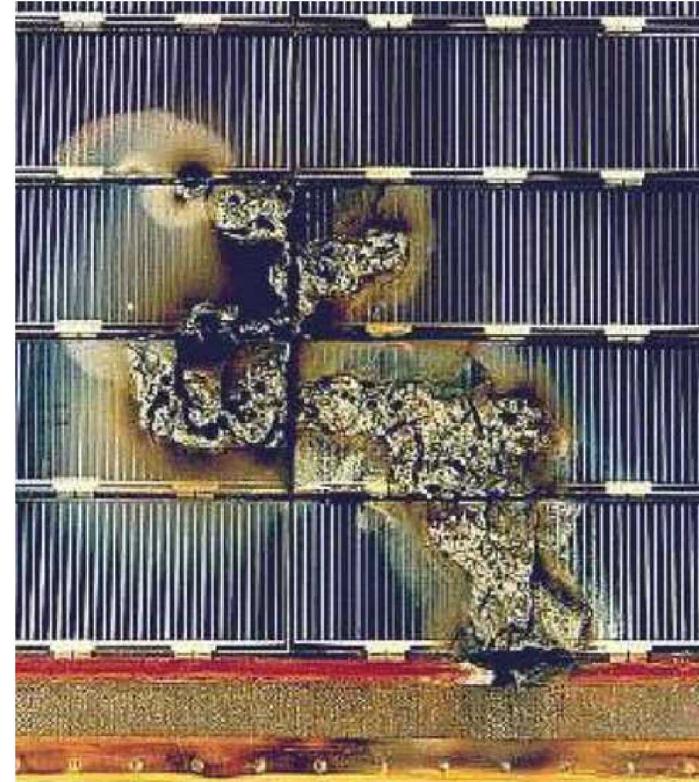
Electrons will accumulate charge on a spacecraft (especially when travelling through Van Allen belts (MEO))

Low energy electrons accumulate on surface, high energy may penetrate and collect internally (for example, in dielectrics)

Field build up and eventual electrostatic discharge (ESD) can cause function interruption or failure

Insulator charging is an important issue. If charge is collected faster than it is dissipated, it will eventually arc

Mitigation: Design and material selection, orbit selection



ESD Damage on Solar Array, NASA.

## Conclusion

The space radiation environment is complex and has many components

The radiation can cause a variety of effects that may hinder a system's ability to perform its mission

We can design a system and model/predict radiation effects to minimize the risk of radiation issues